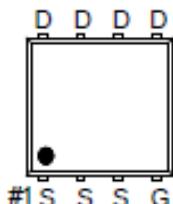


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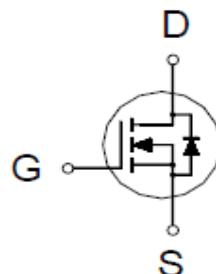
N-Channel Enhancement Mode MOSFET

PRODUCT SUMMARY

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
30V	20mΩ @ $V_{GS} = 10V$	25A



PDFN 3X3S



ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ C$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS	SYMBOL	LIMITS	UNITS
Drain-Source Voltage	V_{DS}	30	V
Gate-Source Voltage	V_{GS}	± 20	
Continuous Drain Current	I_D	25	A
		16	
		8	
		6	
Pulsed Drain Current ¹	I_{DM}	60	
Avalanche Current	I_{AS}	17	
Avalanche Energy	E_{AS}	15	mJ
Power Dissipation	P_D	20	W
		8	
		2	
		1.3	
Operating Junction & Storage Temperature Range	T_J, T_{stg}	-55 to 150	°C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE		SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Ambient	Steady-State	$R_{\theta JA}$		60	°C / W
Junction-to-Case	Steady-State	$R_{\theta JC}$		6	

¹Pulse width limited by maximum junction temperature.

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ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ\text{C}$, Unless Otherwise Noted)

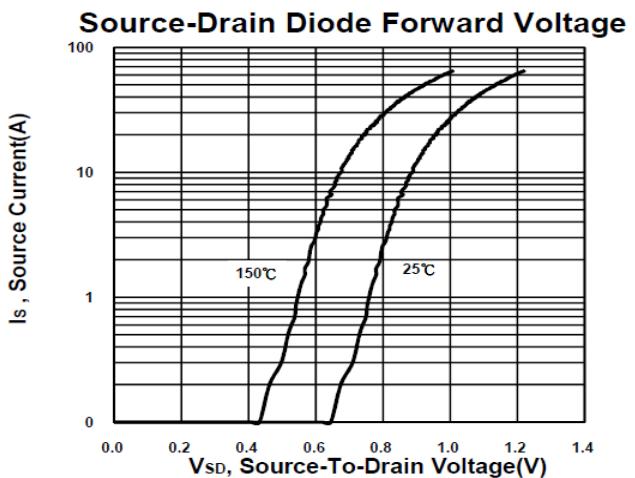
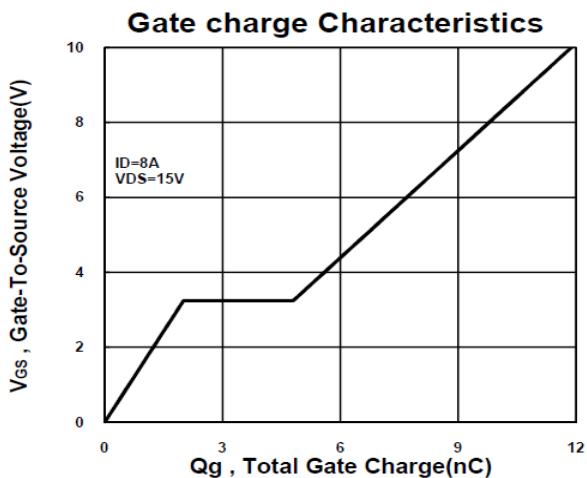
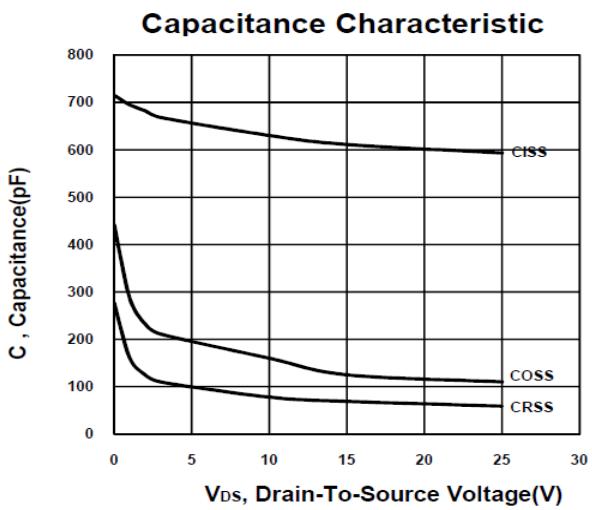
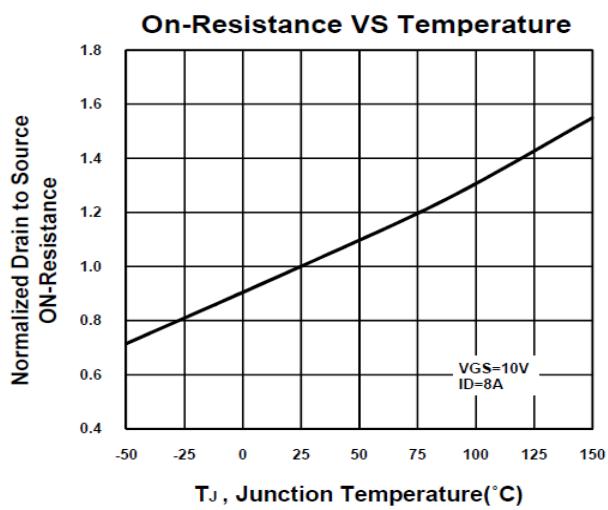
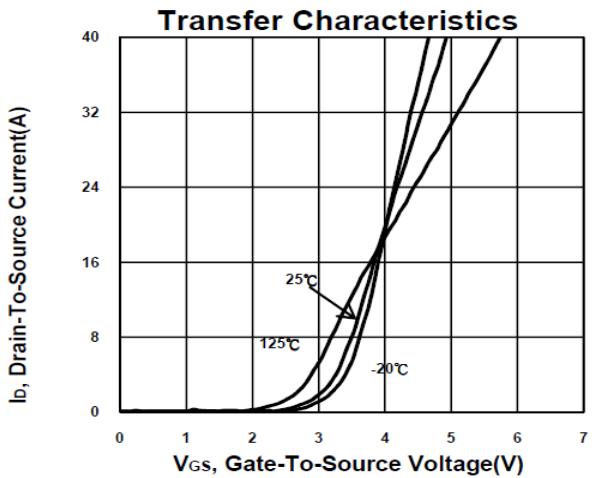
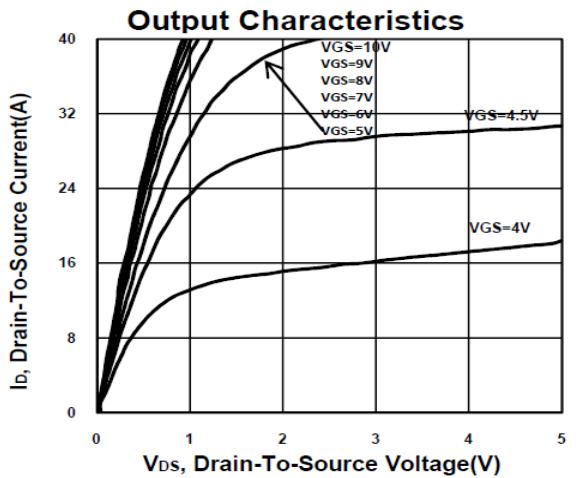
PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNITS
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{\text{GS}} = 0\text{V}, I_D = 250\mu\text{A}$	30			V
Gate Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{DS}} = V_{\text{GS}}, I_D = 250\mu\text{A}$	1	1.8	2.5	
Gate-Body Leakage	I_{GSS}	$V_{\text{DS}} = 0\text{V}, V_{\text{GS}} = \pm 20\text{V}$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{\text{DS}} = 24\text{V}, V_{\text{GS}} = 0\text{V}$			1	μA
		$V_{\text{DS}} = 20\text{V}, V_{\text{GS}} = 0\text{V}, T_J = 55^\circ\text{C}$			10	
On-State Drain Current ¹	$I_{\text{D}(\text{ON})}$	$V_{\text{DS}} = 5\text{V}, V_{\text{GS}} = 10\text{V}$	60			A
Drain-Source On-State Resistance ¹	$R_{\text{DS}(\text{ON})}$	$V_{\text{GS}} = 4.5\text{V}, I_D = 6\text{A}$		28.2	31	$\text{m}\Omega$
		$V_{\text{GS}} = 10\text{V}, I_D = 8\text{A}$		17.6	20	
Forward Transconductance ¹	g_{fs}	$V_{\text{DS}} = 10\text{V}, I_D = 8\text{A}$		16		S
DYNAMIC						
Input Capacitance	C_{iss}	$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = 15\text{V}, f = 1\text{MHz}$		625		pF
Output Capacitance	C_{oss}			130		
Reverse Transfer Capacitance	C_{rss}			73		
Gate Resistance	R_g	$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = 0\text{V}, f = 1\text{MHz}$		2.6		Ω
Total Gate Charge ²	$Q_g(V_{\text{GS}}=10\text{V})$	$V_{\text{DS}} = 0.5V_{(\text{BR})\text{DSS}}, I_D = 8\text{A}$		12.1		nC
	$Q_g(V_{\text{GS}}=4.5\text{V})$			6.3		
Gate-Source Charge ²	Q_{gs}			2.1		
Gate-Drain Charge ²	Q_{gd}			3.1		
Turn-On Delay Time ²	$t_{\text{d}(\text{on})}$	$V_{\text{DD}} = 15\text{V}, I_D \geq 8\text{A}, V_{\text{GEN}} = 10\text{V}, R_G = 3\Omega$		12		nS
Rise Time ²	t_r			12		
Turn-Off Delay Time ²	$t_{\text{d}(\text{off})}$			20		
Fall Time ²	t_f			13		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_J = 25^\circ\text{C}$)						
Continuous Current	I_S				25	A
Forward Voltage ¹	V_{SD}	$I_F = 8\text{A}, V_{\text{GS}} = 0\text{V}$			1	V
Reverse Recovery Time	t_{rr}	$I_F = 8\text{A}, dI_F/dt = 100\text{A}/\mu\text{s}$		30		nS
Reverse Recovery Charge	Q_{rr}			16		nC

¹Pulse test : Pulse Width $\leq 300\ \mu\text{sec}$, Duty Cycle $\leq 2\%$.

²Independent of operating temperature.

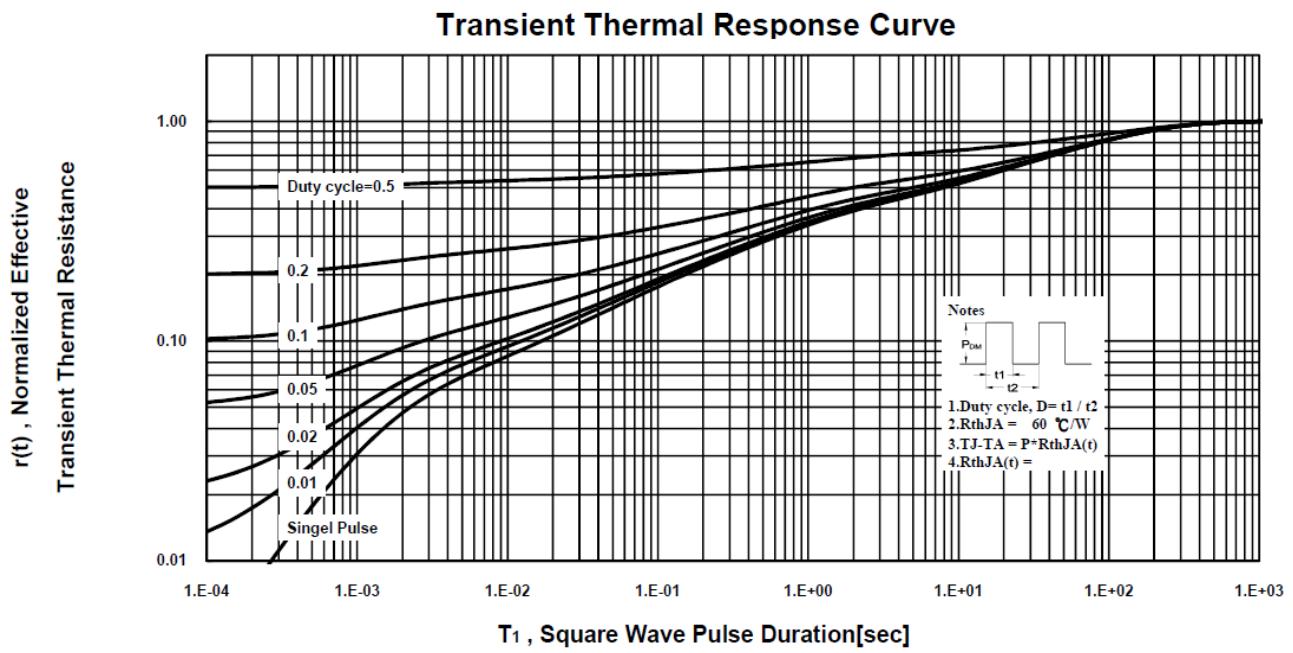
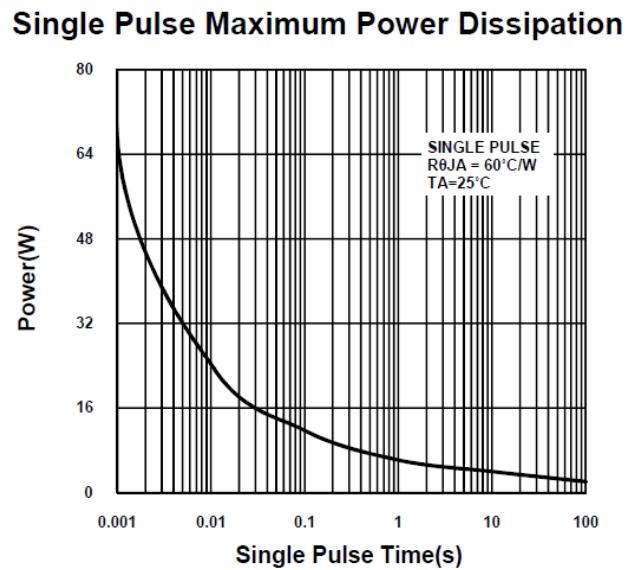
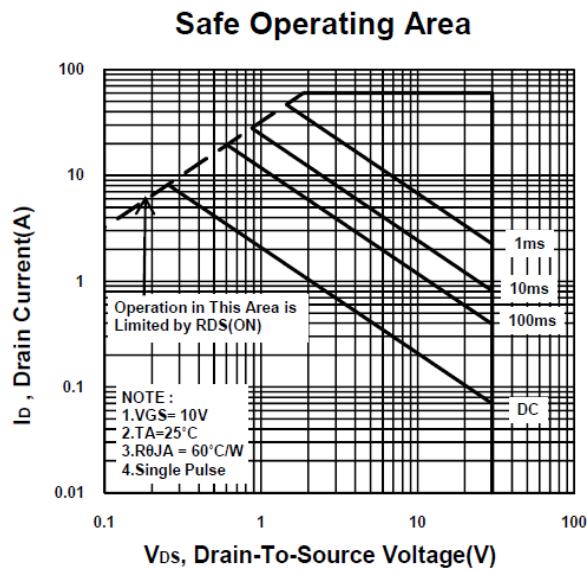
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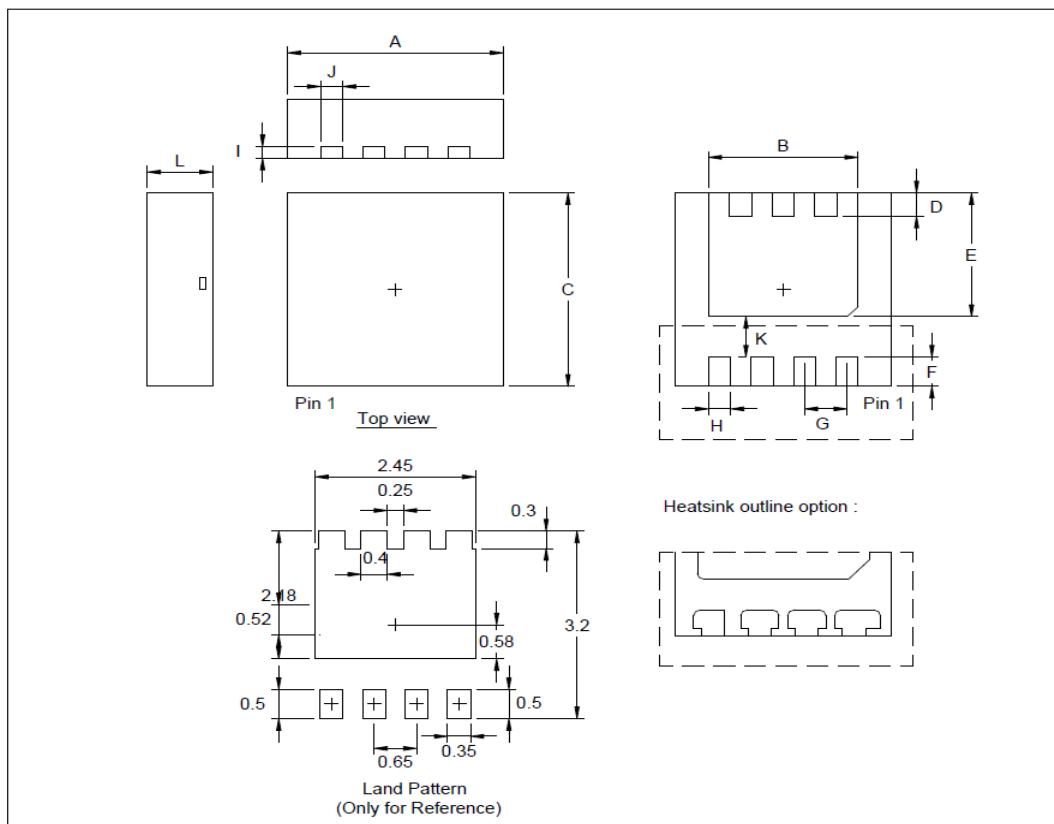
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N-Channel Enhancement Mode MOSFET

Package Dimension

PDFN 3x3S MECHANICAL DATA

Dimension	mm			Dimension	mm		
	Min.	Typ.	Max.		Min.	Typ.	Max.
A	2.9	3.0	3.1	I		0.20	
B	2.35	2.4	2.55	J	0.27	0.35	0.4
C	2.9	3.0	3.1	K		0.45	
D	0.32	0.4	0.45	L	0.7	0.8	0.9
E	2.0	2.1	2.2				
F	0.32	0.42	0.47				
G		0.65					
H	0.27	0.35	0.525				



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